



Surface Waves for Monitoring of Materials at Different Scales

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submissions:

closed (15 December 2019)

Message from the Guest Editors

Dear Colleagues,

This Special Issue of *Applied Sciences* on “Surface Waves for Monitoring of Materials at Different Scales” intends to explore new trends for the application of surface waves at different length scales, welcoming high-quality papers on the following basic topics:

- The use of surface waves for the monitoring of innovative materials
- New data processing and analysis methodologies
- Innovative experimental applications of Rayleigh waves
- Theoretical and numerical studies of wave propagation
- Characterization of mechanical properties and stiffness
- Polarization of surface waves
- Non-linear Rayleigh waves
- Characterization of distributed heterogeneity and layered media
- Advances in scanning acoustic microscopy
- Advances in soil characterization

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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